

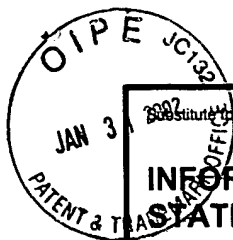
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Complete if Known	
		Application Number	09/875,660
		Filing Date	June 5, 2001
		First Named Inventor	Lambert et al.
		Group Art Unit	2858 2861
		Examiner Name	Hai C. Pham
Attorney Docket Number	ACS 58284		
Sheet	1	of	2

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Examiner Initials	Cite No.	U.S. Patent Document No.		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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		6,096,379		Eckhoff	08/01/2000	427 / 428
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		5,661,305		Lawrence et al.	08/26/1997	250 / 397
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		Office	Number	Kind Code (if Known)				

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T
b8	6	"Standard Guide for Selection and Calibration of Dosimetry Systems for Radiation Processing", American Society for Testing and Materials, ASTM E 1261-00, West Conshohocken, PA 19428 (2000)	
b8	7	"Standard Practice for Use of Calimetric Dosimetry Systems for Electron Beam Dose Measurements and Dosimeter Calibrations", Annual Book of ASTM Standards, publication E 1631-96, American Society for Testing and Materials, West Conshohocken, PA 19428 (1999)	
b8	8	"Dosimeters, dosimetry and associated equipment, Annex C", ANSI/AAMI/ISO 11137-1995 (1995)	

Examiner Signature	Hai C. Pham	Date Considered	3/11/03
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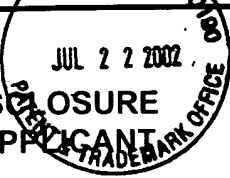
Substitution for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Compleat if Known	
				Application Number	09/875,660
				Filing Date	June 5, 2001
				First Named Inventor	Lambert et al.
				Group Art Unit	2858 2861
				Examiner Name	Hai C. Pham
Sheet	2	of	2	Attorney Docket Number	ACS 58284

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by	°	BOWEN, BRUCE, and SCHNACKENBERG, PAUL, "Thermistor Calibration and the Steinhart-Hart Equation", <u>App Note #4</u> , ILX Lightwave (April, 19 1995), < http://www.ilxlightwave.com/library/appnotes/04/no4i.htm >	
by	°	"Alpha Sensors – Thermal Measurement Solutions – Technical Notes", San Diego, CA (1998), < http://alphasensors.com/technical.html >	
by	°	GREEN, DAN, "Calimetry and Radiation Damage", <i>Radiat. Phys. Chem.</i> Vol. 41, No. 1/2, pp. 19-30, 1993, Printed in Great Britain	
by	°	SAPOFF, M. et al., "The exactness of fit of resistance-temperature data of thermistors with third-degree polynomials", in <u>Temperature Its Measurement and Contrl in Science and Industry</u> Vol. 5, pages 875-887, ed. J. Schooley, American Institute of Physics, New York, NY (1982)	

Examiner Signature	Hai C. Pham	Date Considered	3/11/03
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Substitute for form 1449A/PTO				Complete if Known	
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		Filing Date		June 5, 2001	
		First Named Inventor		Byron Lambert, et al.	
		Group Art Unit		2858 2961	
		Examiner Name		Not yet assigned Hai C. Pham	
Sheet	1	of	1	Attorney Docket Number ACS-58284 (1931P)	

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		Office	Number	Kind Code (if Known)			
HP	5	WO	WO 00/55599		CRYOVAC, INC.	09/21/2000	

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